## Nanoscale



ELECTRONIC SUPPLEMENTARY MATERIAL

## Thin Film Synthesis of SbSI Micro-Crystals for Self-Powered Photodetectors with Rapid Time Response

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 $\label{eq:Fig. 1} \mbox{ Fig. 1 Photograph of an amorphous $Sb_2S_3$ sample and a $SbSI sample after conversion with $SbI_3$ and rinsing in ethanol. }$ 



Fig. 2 Schematic of the evaporation procedure to convert amorphous  $Sb_2S_3$  to crystalline SbSI. The conversion process is complete after only 15 min.



Fig. 3 Temperature curve of the Sbl<sub>3</sub> target on the hot plate (blue), and the sample at the top of the reaction chamber (yellow). The temperatures were measured using a Pt100 temperature sensor.



Fig. 4 XRD reference of a FTO-glass substrate.



Fig. 5 (a) Top and (b) cross-sectional SEM images of an initial amorphous  $Sb_2S_3$  layer on a FTO substrate.



Fig. 6 Cross-sectional SEM micrographs showing the preferential orientation of SbSI crystal needles perpendicular to the substrate surface. Note that these samples had an additional mesoporous ITO layer that was deposited onto the FTO substrate prior to the formation of SbSI. This additional layer is however not necessary and was omitted in the characterised photodetectors.



Fig. 7 (a) Photocurrent versus irradiance of the photodetector at zero bias voltage ( $V_b = 0 V$ ). (b) Spectral response of the photodetector at  $V_b = 0 V$ .



Fig. 8 Signal-to-noise ratio *SNR*, responsivity *R* and specific detectivity  $D^*$  as a function of the illumination irradiance  $E_e$  at zero bias  $V_b = 0$  V.



**Fig. 9** (a) Linear and (b) logarithmic plot of the dark- and photocurrent of the photodetector for different bias voltages  $V_b$ . The lower frame shows corresponding signal-to-noise ratios *SNR*. The *SNR* is highest for low bias voltages, due to the low dark currents.



**Fig. 10** (a) Schematic drawing of a photodetector incorporating an additional layer of gold (thickness 7.5 nm) on top of the FTO electrode, demonstrating the effect of symmetrical electrode work functions, compared to asymmetric work functions in Figures ?? and 9. (b) Dark- and photocurrent of the photodetector with the additional gold layer as a function of bias voltages  $V_{\rm b}$ . (c) Logarithmic plot of the same measurement. The lower frame shows the corresponding signal-to-noise ratios *SNR*.

Table 1 Comparison of the figures of merit of SbSI, perovskite-based and a high performance CdSe-nanowire photodetector

| Photodetector  | $I_{\text{light}}^{a}$    | SNR  | Detectivity $D^*$      | Rise time $	au_{ m r}$ | Fall time $	au_{ m f}$ | Reference |
|--|---------------------------|------|------------------------|------------------------|------------------------|-----------|
| "sandwich" SbSI  | 54 nA                     | 1373 | $6.8 \cdot 10^{9}$     | 8 ms                   | 34ms                   | This work |
| single-crystal SbSI  | $\approx 1.8\mathrm{nA}$  | 700  | $pprox 2.3 \cdot 10^9$ | 300 ms                 | 300 ms                 | 1         |
| Perovskite (CH <sub>3</sub> NH <sub>3</sub> PbI <sub>3</sub> ) | $\approx 10  \mathrm{nA}$ | 92   |                        | 1200 ms                | 200 ms                 | 2         |
| CdSe-nanowire <sup>b</sup>                                     | _                         | 107  | $4 \cdot 10^{13}$      | 350 ns                 | 350 ns                 | 3         |

 $\overline{a} V_{b} = 0.1 \text{ V}, E_{e} = 100 \frac{\text{mW}}{\text{cm}^{2}}, b$  No self-powered mode possible.

## References

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